Product data sheet

1. General description

Planar passivated very sensitive gate four quadrant triac in a SOT54 (TO-92) plastic package intended for use in applications requiring enhanced noise immunity and direct interfacing to logic ICs and low power gate drivers.

2. Features and benefits

- Direct interfacing to logic level ICs
- Enhanced current surge capability
- · Enhanced noise immunity
- High blocking voltage capability
- Planar passivated for voltage ruggedness and reliability
- Triggering in all four quadrants
- Very sensitive gate in four quadrants

3. Applications

- General purpose low power motor control
- Home appliances
- · Industrial process control
- Low power AC Fan controllers

4. Quick reference data

Table 1. Quick reference data

Parameter	Conditions		Min	Тур	Max	Unit
repetitive peak off- state voltage			-	-	600	V
RMS on-state current	full sine wave; $T_{lead} \le 45$ °C; $\overline{Fig. 1}$; $\overline{Fig. 2}$; $\overline{Fig. 3}$		-	-	1	Α
non-repetitive peak on- state current	full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 20 \text{ ms}$; Fig. 4; Fig. 5		-	-	12.5	A
	full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 16.7 \text{ ms}$		-	-	13.8	Α
junction temperature			-	-	125	°C
eristics						
gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 7$		0.2	-	3	mA
	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ \text{ G-};$ $T_j = 25 \text{ °C}; Fig. 7$		0.2	-	3	mA
	repetitive peak off- state voltage RMS on-state current non-repetitive peak on- state current junction temperature	repetitive peak off-state voltage $ \begin{array}{ll} \text{RMS on-state current} & \text{full sine wave; $T_{lead} \leq 45 ^{\circ}\text{C}$; $Fig. 1$;} \\ \hline \text{Fig. 2; Fig. 3} \\ \hline \text{non-repetitive peak on-state current} & \text{full sine wave; $T_{j(init)} = 25 ^{\circ}\text{C}$;} \\ \hline t_p = 20 \text{ms; } \hline \text{Fig. 4; Fig. 5} \\ \hline \text{full sine wave; $T_{j(init)} = 25 ^{\circ}\text{C}$;} \\ \hline t_p = 16.7 \text{ms} \\ \hline \text{junction temperature} \\ \hline \\ \hline \textbf{gate trigger current} & V_D = 12 \text{V; } I_T = 0.1 \text{A; } T2 + \text{G+;} \\ \hline T_j = 25 ^{\circ}\text{C; } \hline \hline \text{Fig. 7} \\ \hline V_D = 12 \text{V; } I_T = 0.1 \text{A; } T2 + \text{G-;} \\ \hline \end{array} $	repetitive peak off-state voltage $ \begin{array}{ll} \text{RMS on-state current} & \text{full sine wave; $T_{lead} \leq 45 ^{\circ}\text{C; Fig. 1;} \\ \hline \text{Fig. 2; Fig. 3} \\ \text{non-repetitive peak on-state current} & \text{full sine wave; $T_{j(init)} = 25 ^{\circ}\text{C;}$ \\ \hline t_p = 20 \text{ms; Fig. 4; Fig. 5} \\ \hline \text{full sine wave; $T_{j(init)} = 25 ^{\circ}\text{C;}$ \\ \hline t_p = 16.7 \text{ms} \\ \hline \text{junction temperature} \\ \\ \hline \textbf{gate trigger current} & V_D = 12 \text{V; } I_T = 0.1 \text{A; T2+ G+;} \\ \hline T_j = 25 ^{\circ}\text{C; Fig. 7} \\ \hline V_D = 12 \text{V; } I_T = 0.1 \text{A; T2+ G-;} \\ \hline \end{array} $	repetitive peak off-state voltage $ \begin{array}{c} \text{RMS on-state current} & \text{full sine wave; $T_{lead} \leq 45 ^{\circ}\text{C; Fig. 1;}$} \\ \text{Fig. 2; Fig. 3} & - \\ \text{non-repetitive peak on-state current} & \text{full sine wave; $T_{j(init)} = 25 ^{\circ}\text{C;}$} \\ \text{t}_p = 20 \text{ms; Fig. 4; Fig. 5} & - \\ \text{full sine wave; $T_{j(init)} = 25 ^{\circ}\text{C;}$} \\ \text{full sine wave; $T_{j(init)} = 25 ^{\circ}\text{C;}$} \\ \text{junction temperature} & - \\ \text{eristics} \\ \\ \text{gate trigger current} & V_D = 12 \text{V; } I_T = 0.1 \text{A; } T2 + \text{G+;} \\ T_j = 25 ^{\circ}\text{C; } Fig. 7 \\ \hline V_D = 12 \text{V; } I_T = 0.1 \text{A; } T2 + \text{G-;} \\ \end{array} \begin{array}{c} - \\ 0.2 \\ 0.2 \\ \end{array} $	repetitive peak off-state voltage $ \begin{array}{ccccccccccccccccccccccccccccccccccc$	repetitive peak off-state voltage $ \begin{array}{ccccccccccccccccccccccccccccccccccc$

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2- G-};$ $T_j = 25 \text{ °C}; \frac{\text{Fig. 7}}{}$	0.2	-	3	mA
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2- G+};$ $T_j = 25 \text{ °C}; \frac{\text{Fig. 7}}{}$	0.2	-	5	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	-	-	7	mA
V _T	on-state voltage	I _T = 1.4 A; T _j = 25 °C; <u>Fig. 10</u>	-	1.3	1.6	V
Dynamic chara	acteristics					
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 402 V; T_j = 110 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 12	80	-	-	V/µs
dV _{com} /dt	rate of change of commutating voltage	V_D = 400 V; T_j = 110 °C; dI_{com}/dt = 0.44 A/ms; I_T = 1 A; gate open circuit	0.5	-	-	V/µs

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	T2	main terminal 2		T2—T1
2	G	gate		G sym051
3	T1	main terminal 1		Syllio51
			TO-92 (SOT54)	

6. Ordering information

Table 3. Ordering information

Type number	Package						
	Name	Description	Version				
Z0103MA0	TO-92	plastic single-ended leaded (through hole) package; 3 leads	SOT54				

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7. Limiting values

Table 4. Limiting values
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage		-	600	V
I _{T(RMS)}	RMS on-state current	full sine wave; $T_{lead} \le 45$ °C; Fig. 1; Fig. 2; Fig. 3	-	1	Α
I _{TSM}	non-repetitive peak on- state current	full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 20 \text{ ms}$; Fig. 4; Fig. 5	-	12.5	Α
		full sine wave; $T_{j(init)}$ = 25 °C; t_p = 16.7 ms	-	13.8	Α
l ² t	I ² t for fusing	t _p = 10 ms; SIN	-	0.78	A²s
dl _T /dt	rate of rise of on-state	I _G = 6 mA	-	50	A/µs
	current		-	50	A/µs
		I _G = 10 mA	-	20	A/µs
		I _G = 6 mA	-	50	A/µs
I _{GM}	peak gate current		-	1	Α
P_{GM}	peak gate power		-	2	W
P _{G(AV)}	average gate power	over any 20 ms period	-	0.1	W
T _{stg}	storage temperature		-40	150	°C
Tj	junction temperature		-	125	°C

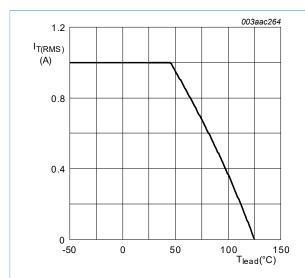


Fig. 1. RMS on-state current as a function of lead temperature; maximum values

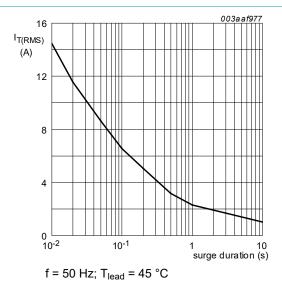


Fig. 2. RMS on-state current as a function of surge duration; maximum values

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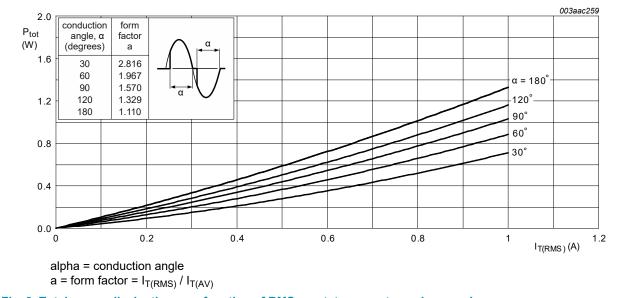


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

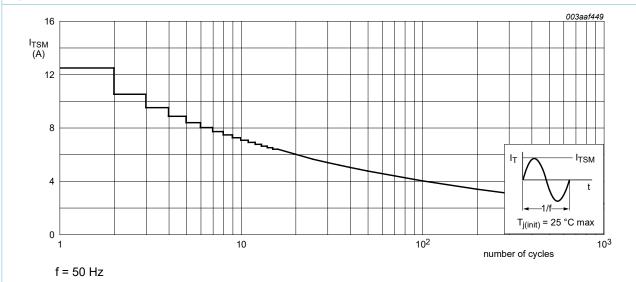
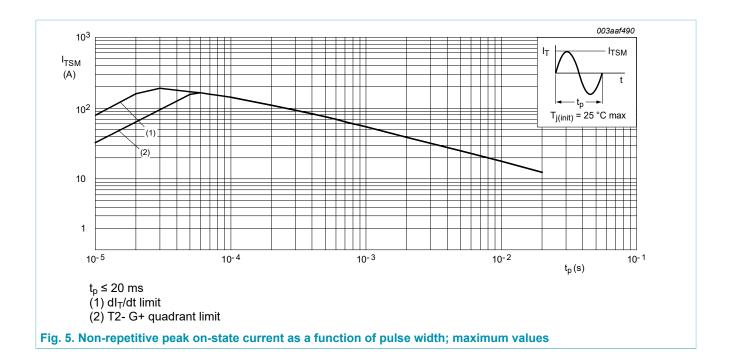


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

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8. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-lead)}	thermal resistance from junction to lead	full cycle; Fig. 6	-	-	60	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient free air	full cycle; printed circuit board mounted; lead length 4 mm	-	150	-	K/W

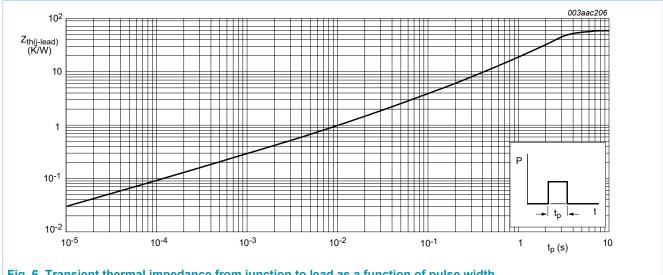


Fig. 6. Transient thermal impedance from junction to lead as a function of pulse width

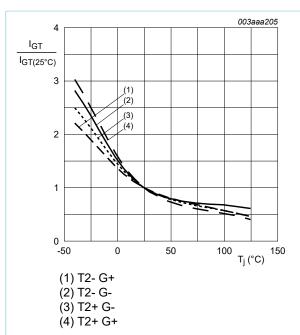
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9. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	acteristics					
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 7$	0.2	-	3	mA
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G-;$ $T_j = 25 \text{ °C}; Fig. 7$	0.2	-	3	mA
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- \text{G-};$ $T_j = 25 \text{ °C}; Fig. 7$	0.2	-	3	mA
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- G+;$ $T_j = 25 \text{ °C}; Fig. 7$	0.2	-	5	mA
I _L	latching current	V _D = 12 V; I _G = 0.1 A; T2+ G+; T _j = 25 °C; <u>Fig. 8</u>	-	-	7	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G-;$ $T_j = 25 \text{ °C}; Fig. 8$	-	-	20	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G-};$ $T_j = 25 ^{\circ}\text{C}; \text{ Fig. 8}$	-	-	7	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G+};$ $T_j = 25 ^{\circ}\text{C}; \text{ Fig. 8}$	-	-	7	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	-	-	7	mA
V _T	on-state voltage	I _T = 1.4 A; T _j = 25 °C; <u>Fig. 10</u>	-	1.3	1.6	V
V_{GT}	gate trigger voltage	V _D = 12 V; I _T = 0.1 A; T _j = 25 °C; Fig. 11	-	-	1	V
		V _D = 600 V; I _T = 0.1 A; T _j = 125 °C; Fig. 11	0.2	-	-	V
I _D	off-state current	V _D = 600 V; T _j = 125 °C	-	-	0.5	mA
Dynamic ch	naracteristics				,	
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 402 V; T_j = 110 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 12	80	-	-	V/µs
dV _{com} /dt	rate of change of commutating voltage	V_D = 400 V; T_j = 110 °C; $dI_{com}/$ dt = 0.44 A/ms; I_T = 1 A; gate open circuit	0.5	-	-	V/µs

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003aaa203 3 I_{L(25°C)} 2 0 -50 0 50 100 150 T_i (°C)

Fig. 8. Normalized latching current as a function of junction temperature



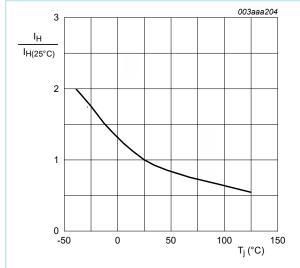
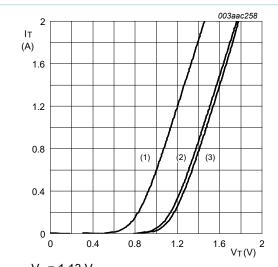


Fig. 9. Normalized holding current as a function of junction temperature



 $V_0 = 1.13 \text{ V}$ $R_s = 0.31 \Omega$

(1) T_j = 125 °C; typical values (2) T_j = 125 °C; maximum values

(3) T_i = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

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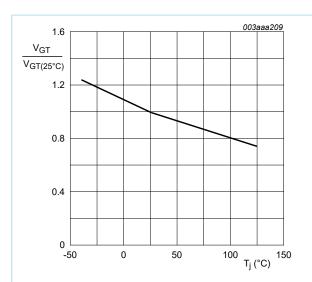


Fig. 11. Normalized gate trigger voltage as a function of junction temperature

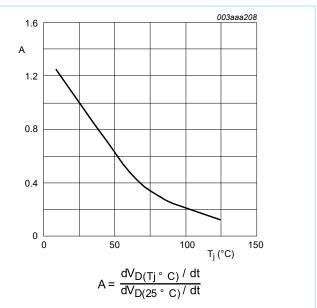
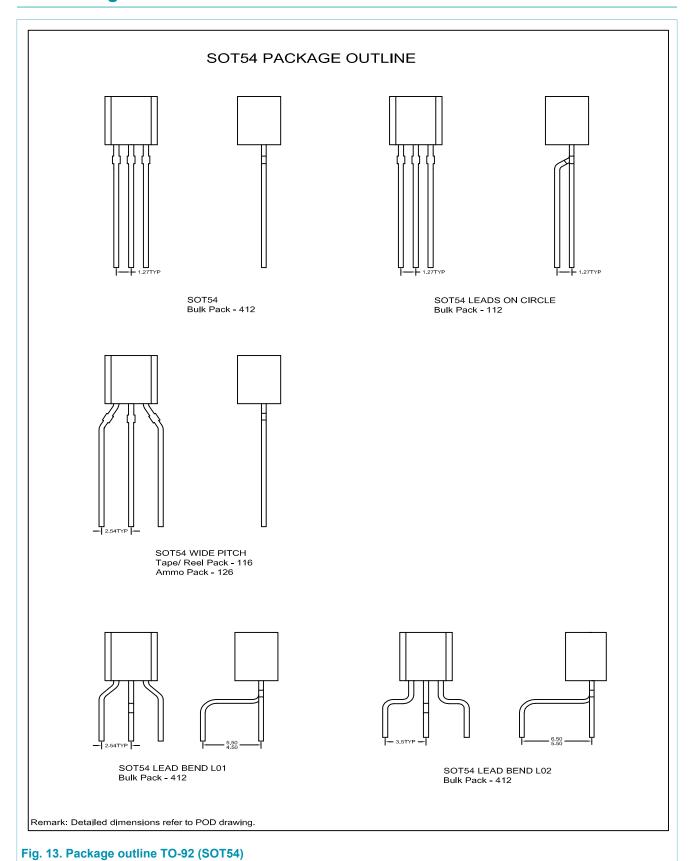


Fig. 12. Normalized critical rate of rise of off-state voltage as a function of junction temperature; typical values

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10. Package outline



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11. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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For more information, please visit: http://www.ween-semi.com
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